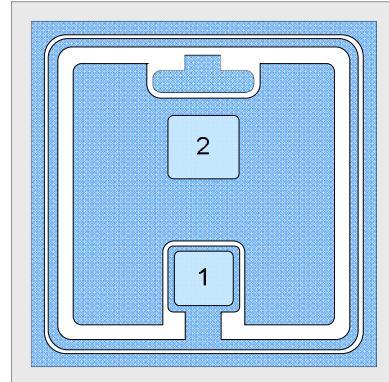


3VD060060NEJL N-CH MOSFET CHIPS WITH ESD PROTECTED STRUCTURE

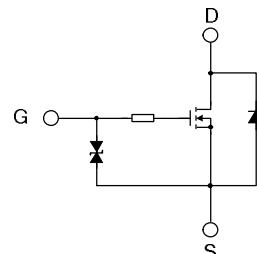
DESCRIPTION

- Ø 3VD060060JL is a N-Channel enhancement mode MOS-FET chip fabricated in advanced silicon epitaxial planar technology.
- Ø Zener diode ESD protected up to 2KV
- Ø High density cell design for low $R_{DS(ON)}$
- Ø Rugged and reliable.
- Ø Fast switching performance.
- Ø High saturation current capability.
- Ø The chips may be packaged in SOT-23 type and the typical equivalent product is 2N7002K.
- Ø The packaged product is widely used in the small servo motor control, power MOS-FET gate drivers, and other switching applications.
- Ø Die size: 0.60mm*0.60mm.
- Ø Chip Thickness: $230\pm20\mu\text{m}$.
- Ø Top metal : Al, Backside Metal : Au.



PAD1: GATE PAD2: SOURCE

CHIP TOPOGRAPHY



EQUIVALENT CIRCUIT

ABSOLUTE MAXIMUM RATINGS ($T_{amb}=25^\circ\text{C}$)

Parameter	Symbol	Ratings	Unit
Drain-Source Voltage	V_{DS}	60	V
Gate-Source Voltage	V_{GS}	± 20	V
Drain Current	I_D	300	mA
Power Dissipation (SOT-23)	P_D	350	mW
Operation Junction Temperature	T_J	150	$^\circ\text{C}$
Storage Temperature	T_{stg}	-55-150	$^\circ\text{C}$

ELECTRICAL CHARACTERISTICS ($T_{amb}=25^\circ\text{C}$)

Parameter	Symbol	Test conditions	Min	Typ	Max	Unit
Drain-Source Breakdown Voltage	$V_{(BR)DS}$	$V_{GS}=0\text{V}$, $I_D=10\mu\text{A}$	60	--	--	V
Gate-Threshold Voltage*	$V_{th(GS)}$	$V_{DS}=V_{GS}$, $I_D=250\mu\text{A}$	1	--	2.5	
Gate-body Leakage	I_{GSS}	$V_{DS}=0\text{V}$, $V_{GS}=\pm 20\text{V}$	--	--	± 10	
Zero Gate Voltage Drain Current	I_{DSs}	$V_{DS}=60\text{V}$, $V_{GS}=0\text{V}$	--	--	1	μA
Drain-Source On-Resistance*	$R_{DS(on)}$	$V_{GS}=10\text{V}$, $I_D=500\text{mA}$	--	--	2.0	Ω
		$V_{GS}=5\text{V}$, $I_D=50\text{mA}$	--	--	3.0	

Note: * Pulse test, pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$